

SYSTEM AND METHOD FOR DETECTING DEFECTS IN A LIGHT-MANAGEMENT FILM

Abstract

A system and a method for detecting defects in a light-management film are provided. The system includes a first light source configured to emit light onto a first side of the film in a first predetermined region of the film. The system further includes a second light source configured to emit light onto a second side of the film in the first predetermined region of the film. The system further includes a first camera configured to receive a first portion of light reflected from the first predetermined region of film from the first light source and a second portion of the light propagating through the film from the second light source. Finally, the system includes a signal-processing device operably coupled to the first camera configured to detect a defect in the first predetermined region of the film based on at least one of the first and second portions of light.